Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination	
10/044,169	CHIU ET AL.	
Examiner	Art Unit	
Ronald Laneau	3627	

SCARGUED						
SEARCHED						
Class	Subclass	Date	Examiner			
705	028	8/4/2006	RL			
705	029	8/4/2006	RL			
705	022	8/4/2006	RL			
705	008	8/4/2006	RL			

INTERFERENCE SEARCHED				
Subclass	Date	Examiner		
028	8/4/2006	RL		
029	8/4/2006	RL.		
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<u> </u>				
	Subclass 028	Subclass Date   028 8/4/2006		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Consulted with SPE Eric Stamber	8/4/2006	RL		
EIC Search	8/2/2006	RL		
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